

**Search Notes**

Application/Control No.

10/005,936

Examiner

Tse Chen

Applicant(s)/Patent under  
Reexamination

MASUYAMA ET AL.

Art Unit

2116

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Consulted J. Trujillo on interpretation of optional claim language	4/5/2007	TC
Inventor name	5/7/2007	TC
713/330 with "server address"	5/7/2007	TC